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PD - 1986-05-12  
PR - JP19840214650 19841013  
OPD - 1984-10-13  
TI - MASS SPECTROMETER  
IN - KAKITA YOSHIKAZU

PA - JEOL LTD  
EC - H01J49/32  
IC - G01N27/62 ; H01J49/04 ; H01J49/26

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TI - Mass analyser combining 2 mass spectrometers - for high resolution spectrum, enables determin. of each peak in corresp. spectrum NoAbstract Dwg2f/7  
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AB - PURPOSE: To obtain the high resolution spectrum of a daughter ion by making the first and second median slits, and a collision chamber integrated with each other movable along an ion passage, with regard to a mass spectrometer consisting of two elementary mass spectrometers.  
- CONSTITUTION: Ions generated in an ion source IS are introduced into the first mass analysis system MS, shot into a collision chamber CC which is integrated with the first and the second median slits S, S' with variable widths and made movable along an

none

none

none

ion passage, and selected specific mother ion collides with a neutral gas molecule in order to generate daughter ions. The daughter ions are introduced to the second mass analyzing system M2, and are detected by a detector ID. MS/MS apparatus is constituted as described above. Therefore, the mother ions are measured with a high resolution by positioning a median focus point on the slit S, and the high resolution spectrum of the daughter ions can be obtained by positioning the median focus point on the slit S'.

SI - G01N27/62

I - H01J49/26 ;H01J49/04

none

none

none